



1. Overview of functions and structural features



Tungsten steel probe



With SZT-C test bench

Basic function: ST2253-F01 type tungsten needle linear four-probe probe, linear 1+1+1 mm needle pitch, high wear-resistant tungsten carbide probe, equipped with four-probe instrument and test bench, for testing silicon semiconductors, Metal, conductive plastics and other hard materials resistivity/square resistance.

Basic composition: The complete set of probes consists of a detachable tungsten carbide probe, a probe clamping unit, a probe and probe pressure buffer spring, a hand-held jacket, a test bench connection unit, an instrument connection cable, and other components.

Matching and Compatibility: This probe is compatible with all four-probe instruments and four-probe test benches of our company. The main models in the table below are compatible with most of the four-probe instruments of other manufacturers.

2. Main technical parameters and description

1 Measurable pieces or bars can be measured. The minimum sample size is $3\text{mm} \times 4\text{mm}$, and the maximum plane size and thickness are determined by the equipped test bench. There is no limit to the way of holding the probe.

2.1 Probe pitch: straight line 1+1+1 mm pitch.

2.2 Probe mechanical movement rate: $\pm 0.5\%$.

2.3 Probe: tungsten carbide, $\Phi 0.5\text{mm}$.

2.4 Pressure: 0~2kg adjustable, rated pressure is about 1.5kg.

3 The probe is a quick-release type, which is convenient for the frequent use of the production line.